



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

2811  
RECEIVED  
FEB -5 2002  
TC 2800 MAIL ROOM

Application of

Applicants : Chandra V. Mouli and Ceredig Roberts  
Serial No. : 09/648,044  
Filed : August 25, 2000  
Confrm No. : 6800  
Title : **METHOD AND DEVICE TO REDUCE GATE-INDUCED DRAIN LEAKAGE (GIDL) CURRENT IN THIN GATE OXIDE MOSFETs**  
Docket No. : MIO 0054 PA  
Examiner : O. Nadav  
Art Unit : 2811

Assistant Commissioner for Patents  
Washington, D.C. 20231

CERTIFICATE OF MAILING	
I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on January 7, 2002.	
William A. Jividen	42,695 Reg. No.

Sir:

**AMENDMENT**

This paper is being filed in response to the Office Action mailed December 5, 2001, thereby having a non-fee response date of no later than March 5, 2002.

Reconsideration and reexamination are respectfully requested in light of the amendments and remarks below.

**In the Drawing**

The Applicant encloses herewith new FIG. 3E illustrating the subject matter described in the specification and claims of the present application for approval by the examiner. It is respectfully submitted that the presently proposed figure drawing more accurately illustrate the recited subject matter of the present invention. No new matter has been entered.

**In the Specification**

Attached hereto as Appendix A is a marked up reproduction of the changes made to the specification and claims by the current amendments. Additions have been underscored and deletions have been stricken.